

# Characterization of High Flux CZT detectors at the ESRF

## Collaboration with IMEM (Parma, Italy)

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- 3. Characterizations under irradiation**
- 4. Analysis**
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## ■ Why did we want to work with Redlen HF-CZT

- Better hole transport properties than standard (aka. spectroscopic) CZT
- ⇒ reduced polarization phenomena

	$\mu_e \tau_e (\times 10^{-4} \text{cm}^2 \cdot \text{V}^{-1})$	$\mu_e (\text{cm}^2 \cdot \text{V}^{-1} \cdot \text{s}^{-1})$	$\tau_e (\times 10^{-6} \text{s})$	$\mu_h \tau_h (\times 10^{-4} \text{cm}^2 \cdot \text{V}^{-1})$	$\mu_h (\text{cm}^2 \cdot \text{V}^{-1} \cdot \text{s}^{-1})$	$\tau_h (\times 10^{-6} \text{s})$
HF-CZT	11±6	940±190	1.2±0.8	2.9±1.4	114±22	2.5±14
Standard CZT	100	1100	11	0.2	88	0.2

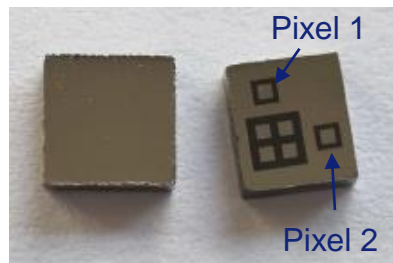
## ■ Objectives of the collaboration with IMEM

- Reduce the leakage current of the devices obtained with HF-CZT
- ⇒ Electrodes optimization (work done by IMEM)
- Characterize the optimized devices (work done at the ESRF)

## ▪ Test samples characteristics

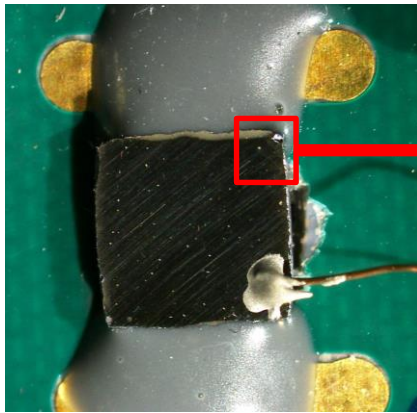
- CZT pixelated detectors were purchased from Redlen and re-processed by IMEM
- Processing at IMEM:
  - *Polishing of existing electrodes*
  - *Deposition of Au (electroless deposition) and/or Pt electrodes (sputtered deposition)*
  - *Substantial work done by IMEM in terms of electrode type and electrode deposition method to reduce the leakage current*

Name	Material	Cathode contact	Anode contact	Geometry (mm <sup>3</sup> )	Pixel size (mm <sup>2</sup> )
Test sample 1   AP	Redlen “high flux” CZT	Au	Pt	5 × 5 × 1.5	0.5 × 0.5
Test sample 2   PP	Redlen “high flux” CZT	Pt	Pt	5 × 5 × 1.5	0.5 × 0.5

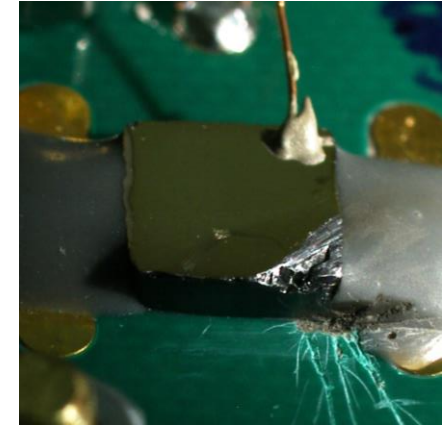


**Notation:** Test sample 1 – pixel 1 ≡ ts1\_px1

## ▪ Electrical breakdown on one corner



*A round trip to Italy and some sanding paper later...*



## ▪ After rescue

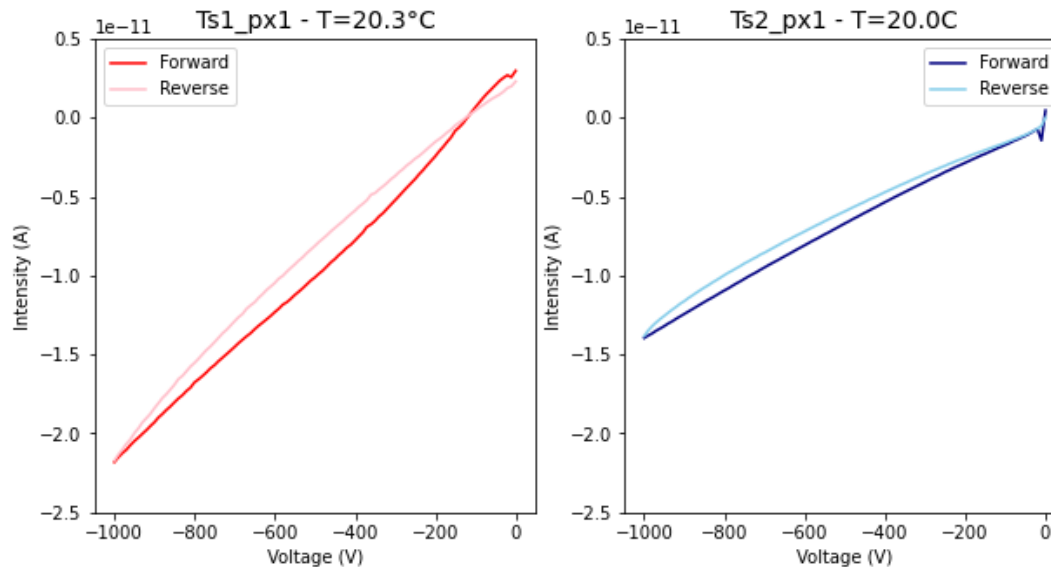
- I-V characteristics (dark and under irradiation) are back to normal with a slight increase of the leakage current

**Despite the damages sustained, the performances remain good!**

## ■ I-V<sub>dark</sub> measurements

- IMEM: Test sample 1:  $J_{\text{dark}} \approx 40\text{pA/mm}^2$  at -800V  
Test sample 2:  $J_{\text{dark}} \approx 40\text{pA/mm}^2$  at -800V
- ESRF: Test sample 1:  $I_{\text{dark}}=1.7 \times 10^{-11}\text{A} \rightarrow J_{\text{dark}} \approx 70\text{pA/mm}^2$  at -800V  
Test sample 2:  $I_{\text{dark}}=1.0 \times 10^{-11}\text{A} \rightarrow J_{\text{dark}} \approx 40\text{pA/mm}^2$  at -800V

- ⇒ 1 order of magnitude improvement compared with standard Redlen pixelated HF-CZT<sup>(1)</sup>
- ⇒ 4 orders of magnitude improvement compared with other electrode configurations tested

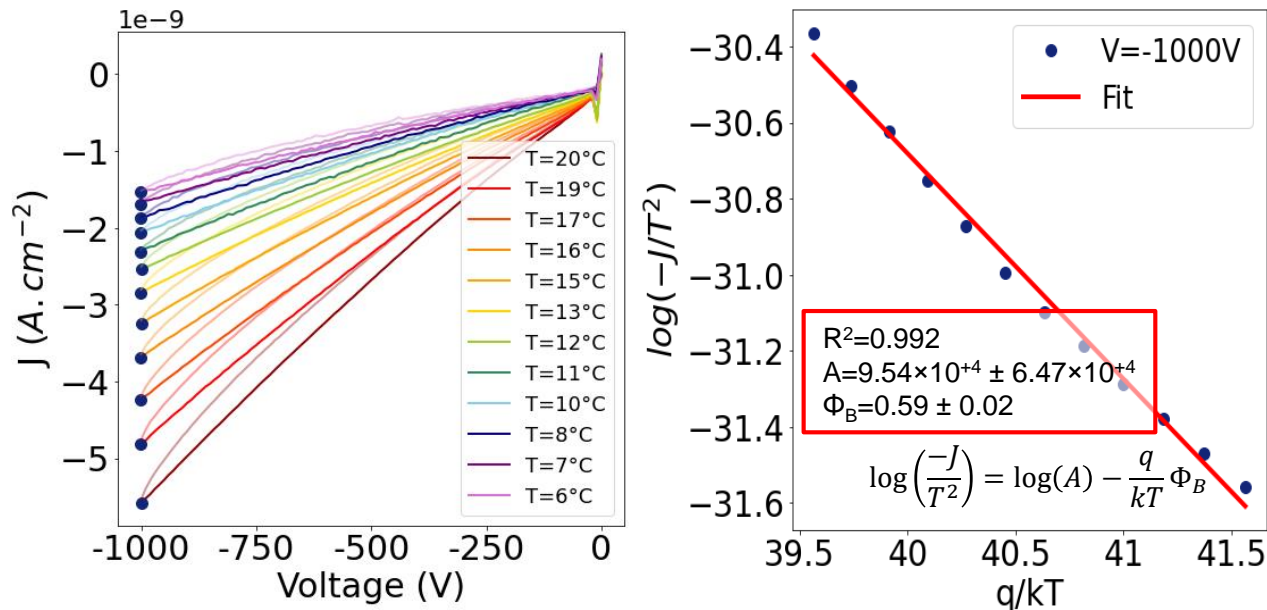


<sup>(1)</sup>doi: 10.1088/1748-0221/14/12/C12009

**Electrode processing lead to reduction of the leakage current (<100pA/mm<sup>2</sup> @-5kV/cm 20°C).**

## ■ Estimation of the Schottky barrier height

- Non-ideal Schottky characteristics: low reverse current and linear characteristics
- Using the thermionic emission model the height of the Schottky barrier was estimated to be  $\Phi_B=0.59\text{eV}$  regardless of the bias voltage.
- ⇒ This is a bit lower than other estimations<sup>(1)</sup> (0.75eV) because of non optimal conditions for the use of the ITD model (bias voltage too low to reach the thermionic dominated current region).

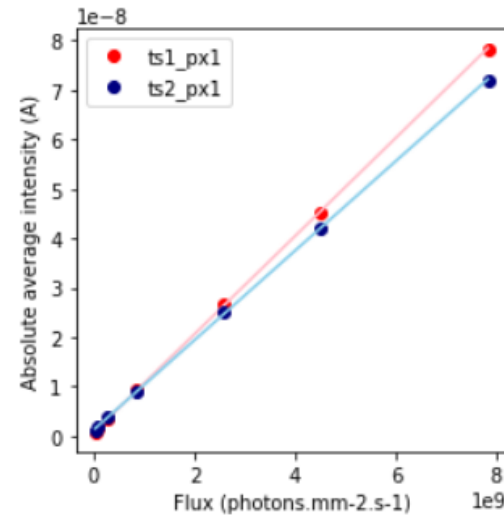
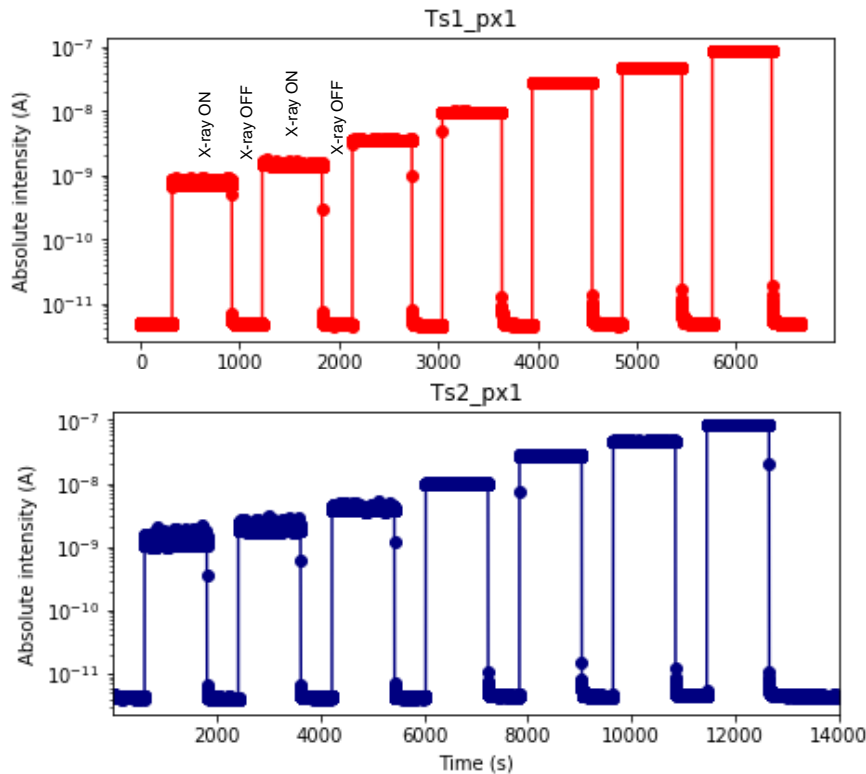


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<sup>(1)</sup>doi: 0.1038/s41598-020-70801-9

## Stability and linearity: pulsed irradiation at 20keV, V=-1000V

- Fluxes range:  $3 \cdot 10^7 \text{ photons} \cdot \text{mm}^{-2} \cdot \text{s}^{-1}$  -  $8 \cdot 10^9 \text{ photons} \cdot \text{mm}^{-2} \cdot \text{s}^{-1}$  (Al filters)
- Test sample 1: 10min under irradiation, 5min without irradiation
- Test sample 2: 20min under irradiation, 10min without irradiation



**Good linearity and stability in the  $10^7$ - $10^{10} \text{ ph} \cdot \text{mm}^{-2} \cdot \text{s}^{-1}$  range.**

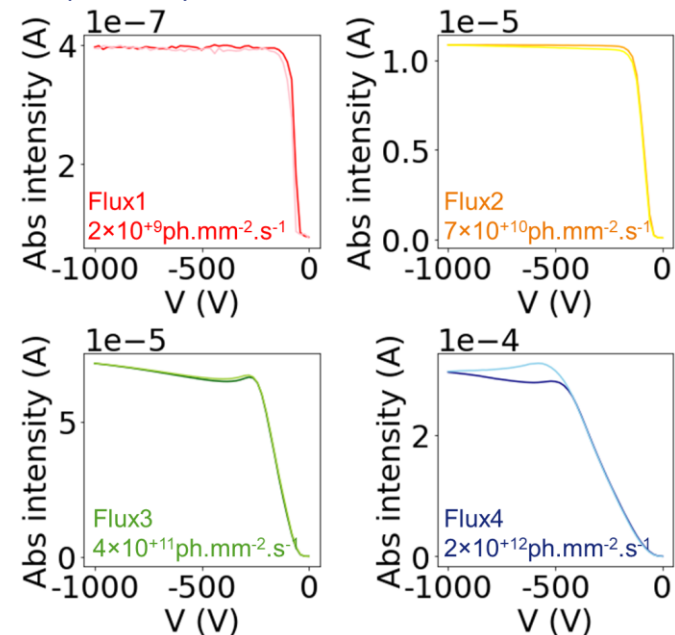
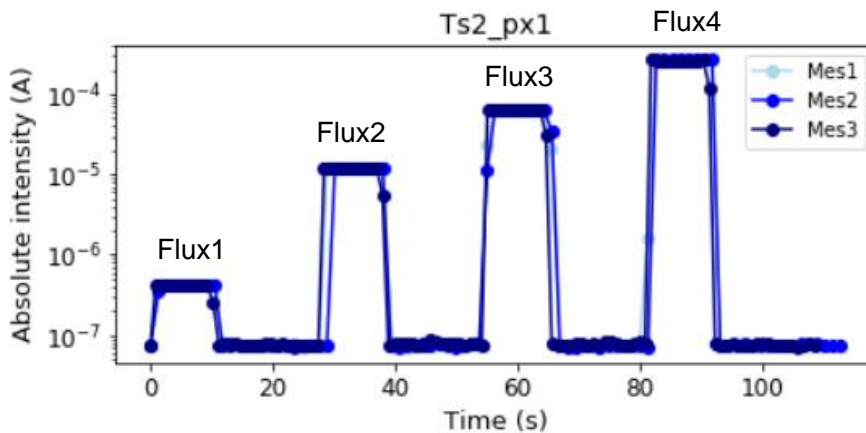


## ▪ Pulsed irradiation at 19keV, V=-500V (ts2\_px1 only)

- Fluxes range estimated:  $2 \cdot 10^{+9}$  photons. $\text{mm}^{-2} \cdot \text{s}^{-1}$  -  $1 \cdot 10^{+12}$  photons. $\text{mm}^{-2} \cdot \text{s}^{-1}$  (2 orders of magnitude higher than BM05 flux, flux adjusted using gap between magnets of the undulators)
- Test sample 2: 10s under irradiation, 15s without irradiation

## ▪ I-V characteristics

- Deformed I-V shapes above  $10^{+11}$  photons. $\text{mm}^{-2} \cdot \text{s}^{-1}$  (Flux 3)



**Stable and reproducible behavior up to  $10^{+12}$  ph. $\text{mm}^{-2} \cdot \text{s}^{-1}$ , deformation and hysteresis appear above  $10^{+11}$  ph. $\text{mm}^{-2} \cdot \text{s}^{-1}$**

# TRANSIENT PHENOMENA: PRELIMINARY RESULTS

Context  
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Dark conditions  
○○

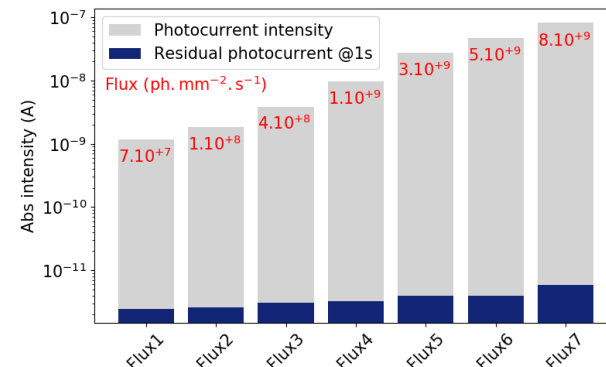
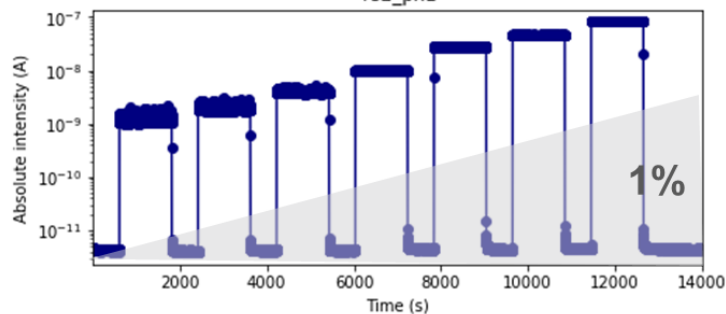
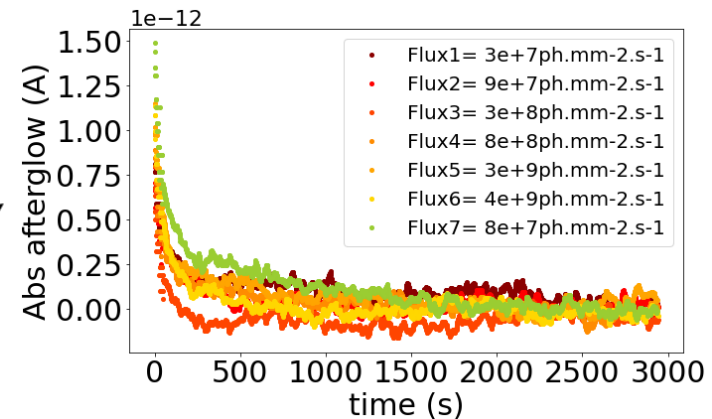
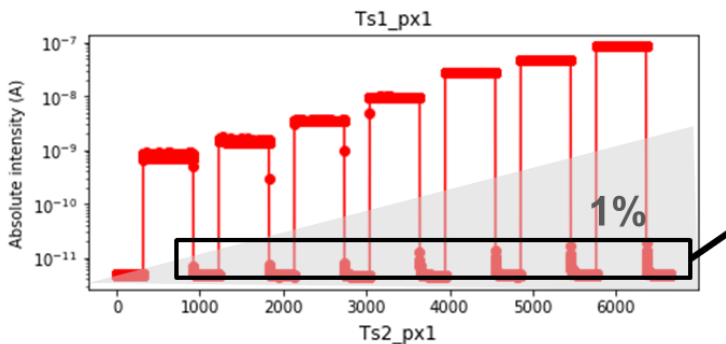
Characterizations under irradiation  
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Analysis  
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Outlook and ongoing work  
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## Residual signal (aka afterglow) and stabilization time on BM05 results:

- Disclaimer: no specific measurement performed, analysis limited to the seconds time range (5Hz rate)
- Stabilization time: rapid rise of the signal (< 200ms)
- Residual signal
  - *Rapid initial drop: within less than 400ms the residual signal is below 1% of the photocurrent*
  - *Going back to dark current value: several hundreds of seconds with no clear link between incident flux and residual signal*
  - *Residual signal at 1s*



# TRANSIENT PHENOMENA: PRELIMINARY RESULTS

Context  
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Dark conditions  
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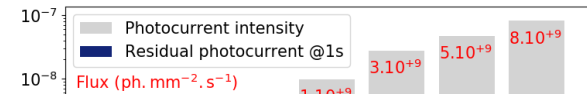
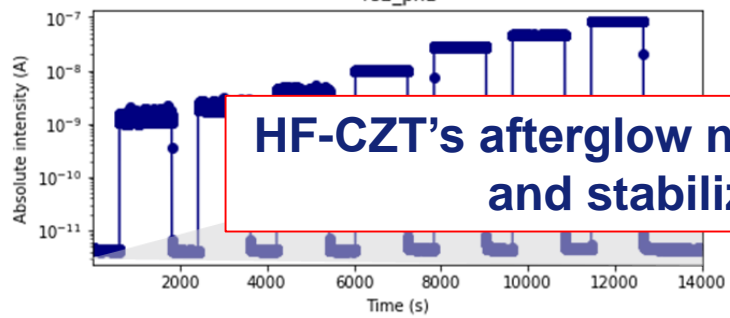
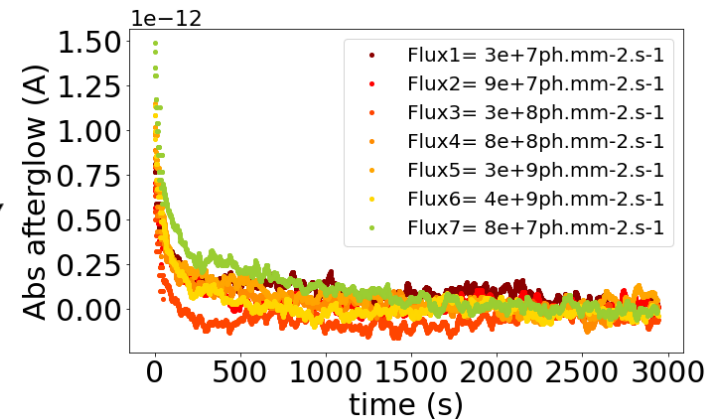
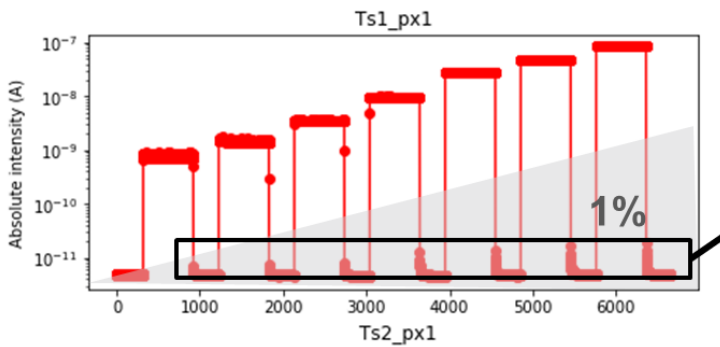
Characterizations under irradiation  
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Analysis  
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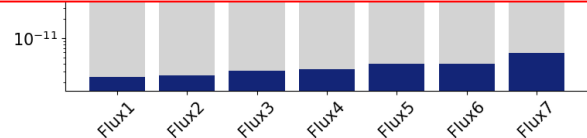
Outlook and ongoing work  
○

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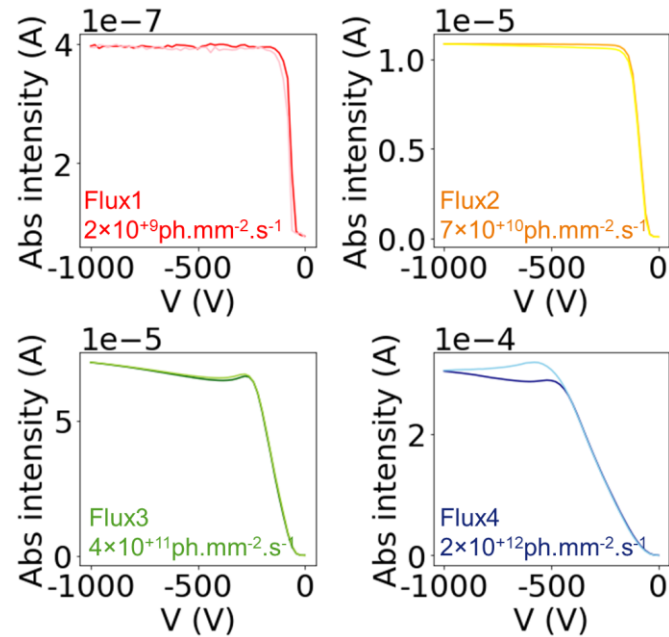


**HF-CZT's afterglow negligible in the seconds time range and stabilization time below 200ms.**

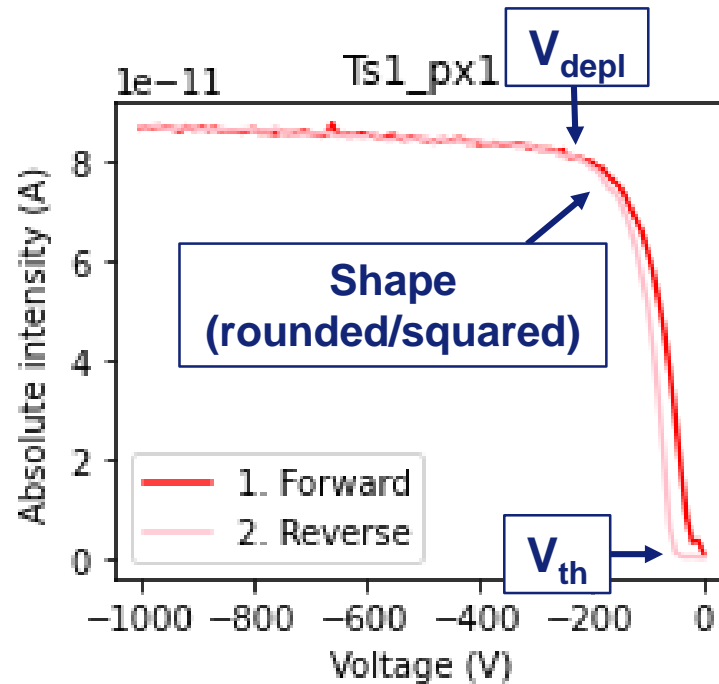


## ■ IV characteristics shape as a function of the incident X-ray flux

- From ID19



- **IV characteristics as a function of the incident X-ray photons' energy**
  - IV characteristics from BM05 and from laboratory X-ray generator



# I-V CHARACTERISTICS SHAPES

Context  
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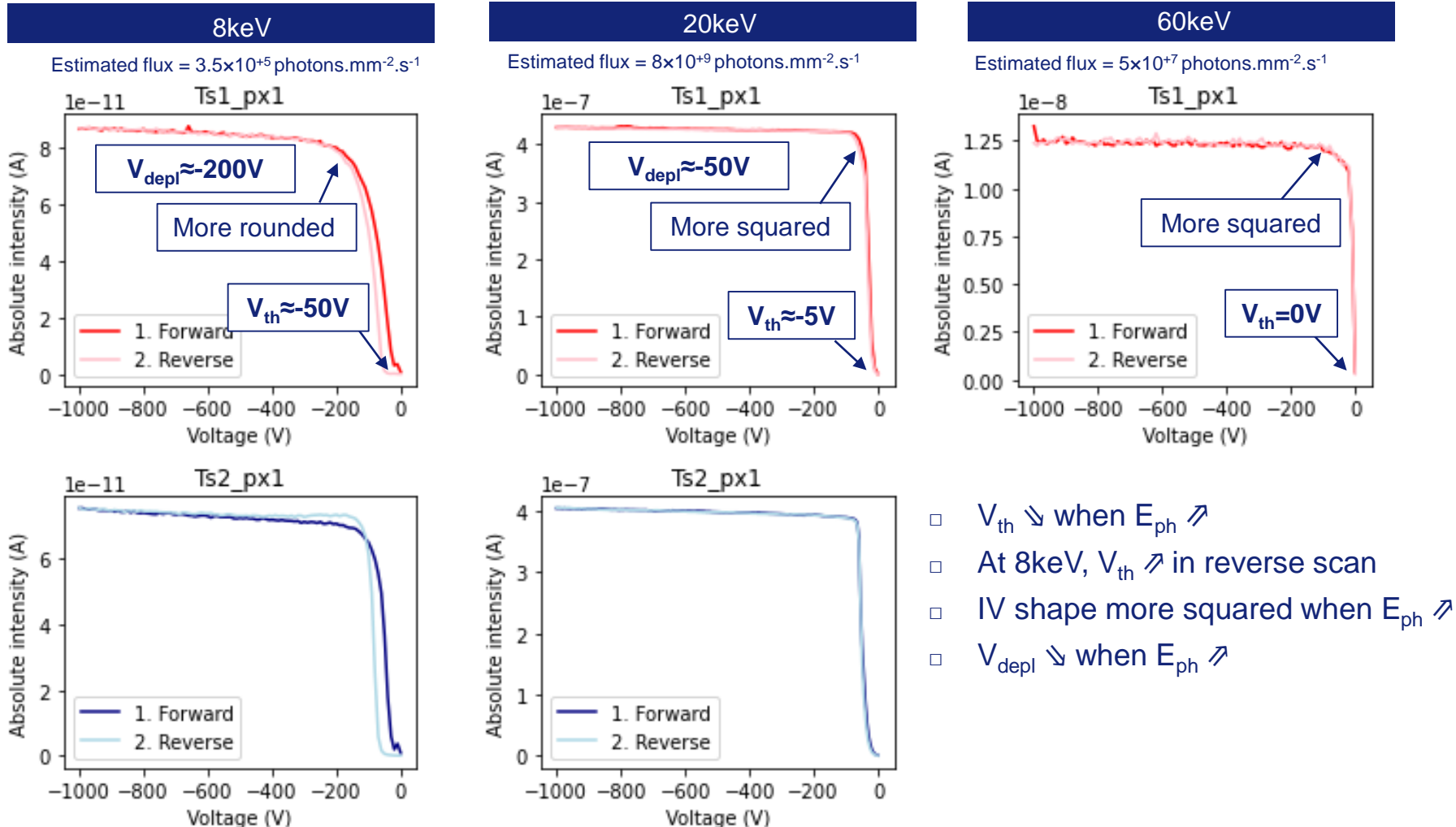
Dark conditions  
○○

Characterizations under irradiation  
○○

Analysis  
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Outlook and ongoing work  
○

## IV characteristics as a function of the incident X-ray photons' energy



- $V_{\text{th}} \searrow$  when  $E_{\text{ph}} \nearrow$
- At 8keV,  $V_{\text{th}} \nearrow$  in reverse scan
- IV shape more squared when  $E_{\text{ph}} \nearrow$
- $V_{\text{depl}} \searrow$  when  $E_{\text{ph}} \nearrow$

**How to explain the differences observed with incident energy?**

# ANALYTICAL RAMO-BASED MODEL

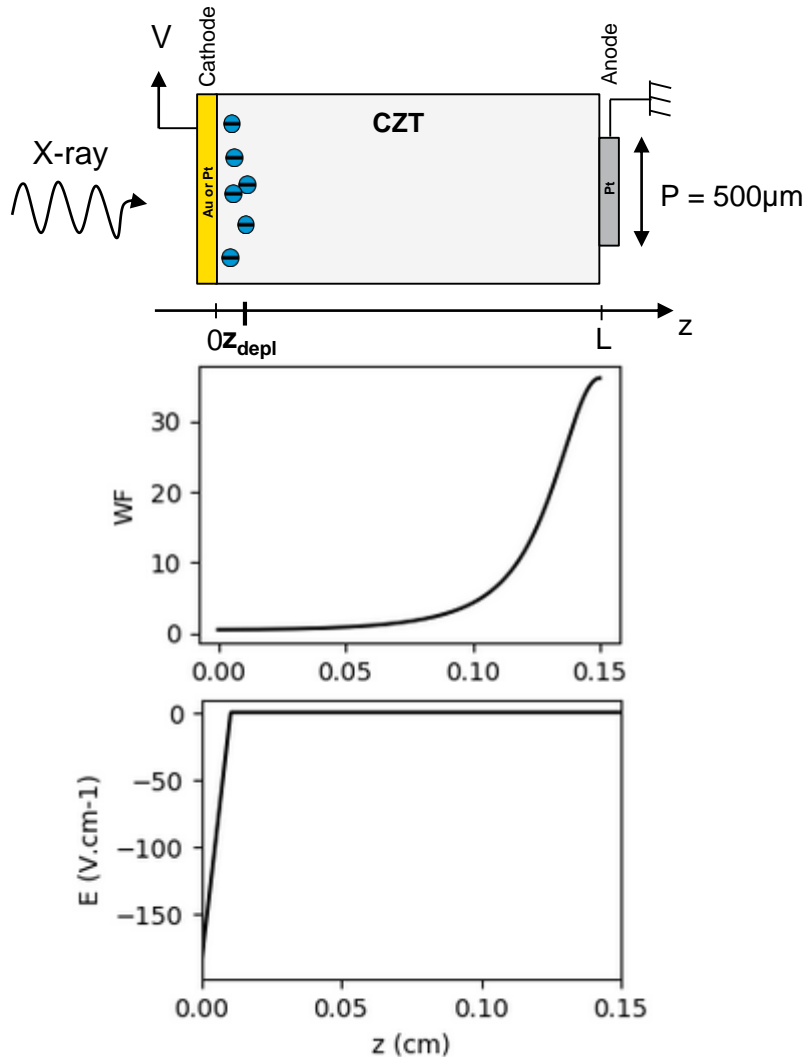
Context  
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Dark conditions  
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Characterizations under irradiation  
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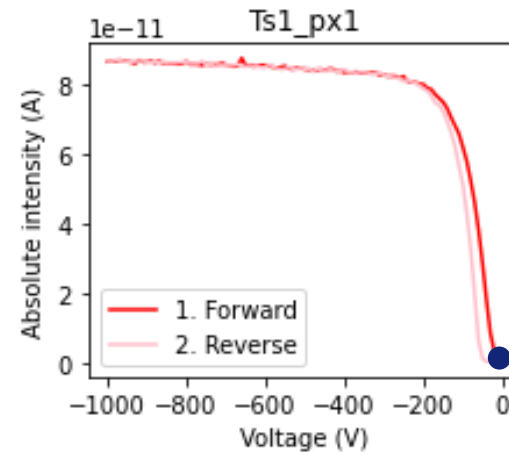
Analysis  
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Outlook and ongoing work  
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$V = -1V$

8keV



# ANALYTICAL RAMO-BASED MODEL

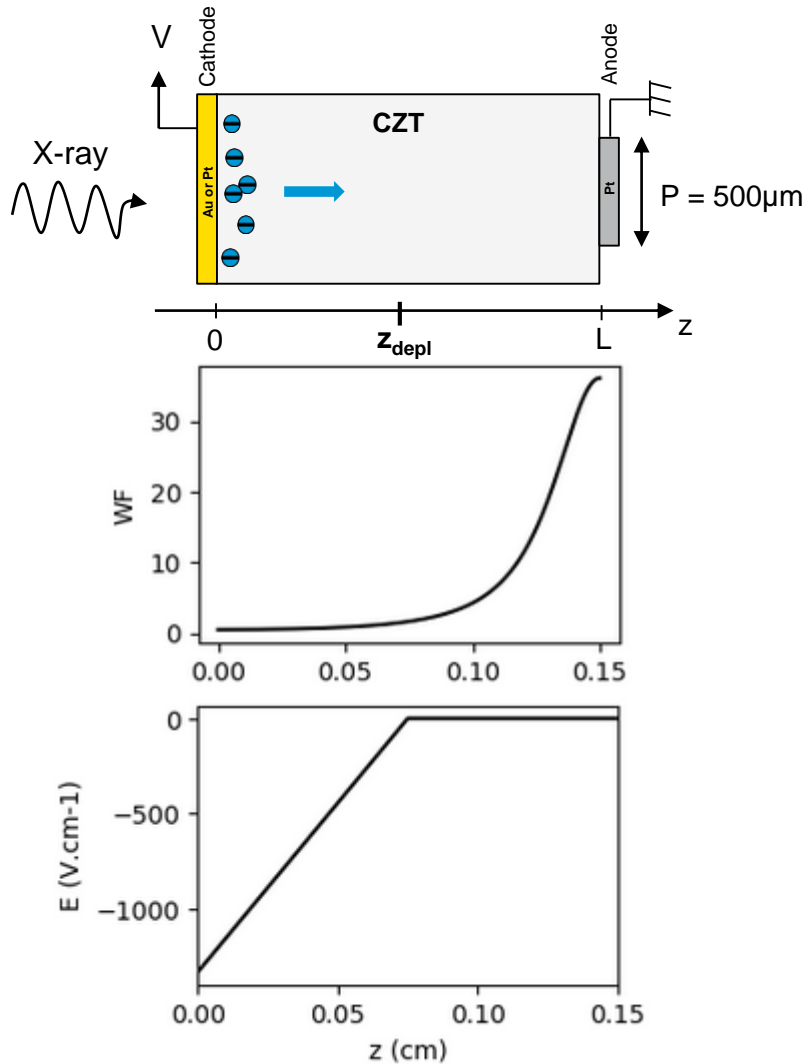
Context  
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Dark conditions  
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Characterizations under irradiation  
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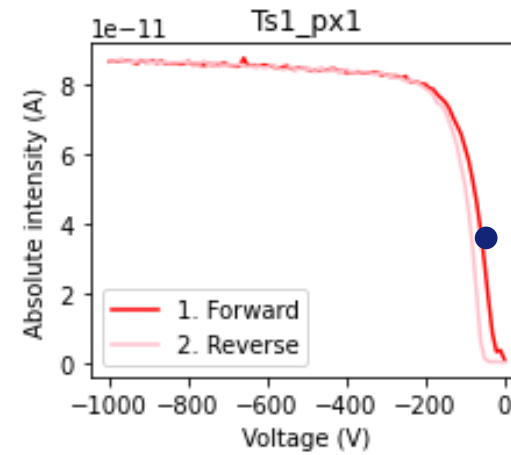
Analysis  
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Outlook and ongoing work  
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**V = -50V**

**8keV**





# ANALYTICAL RAMO-BASED MODEL

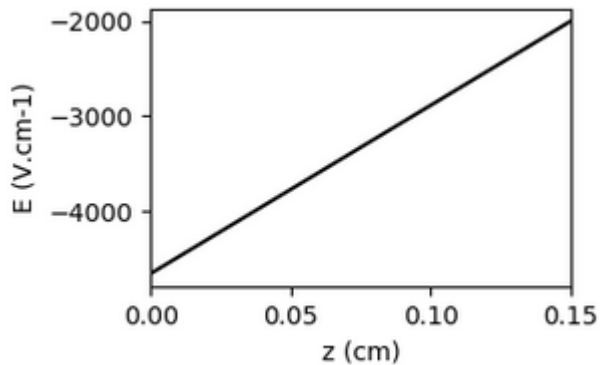
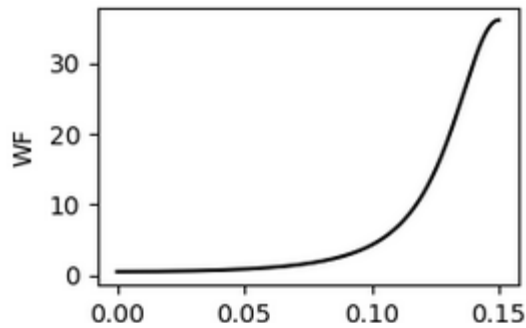
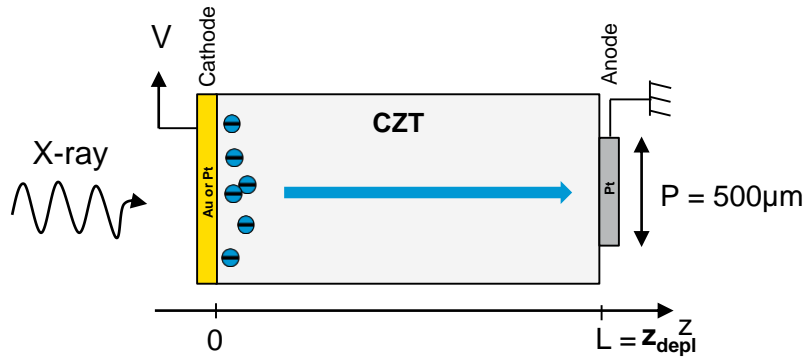
Context  
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Dark conditions  
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Characterizations under irradiation  
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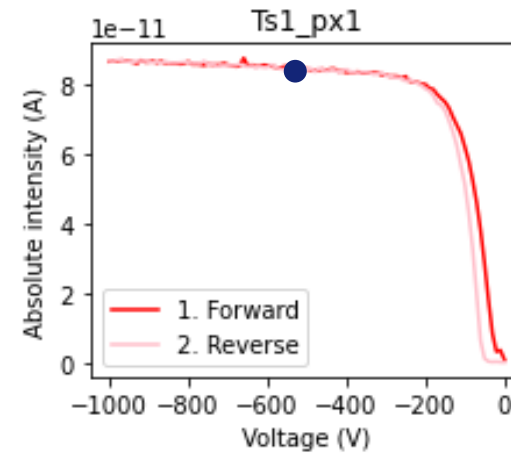
Analysis  
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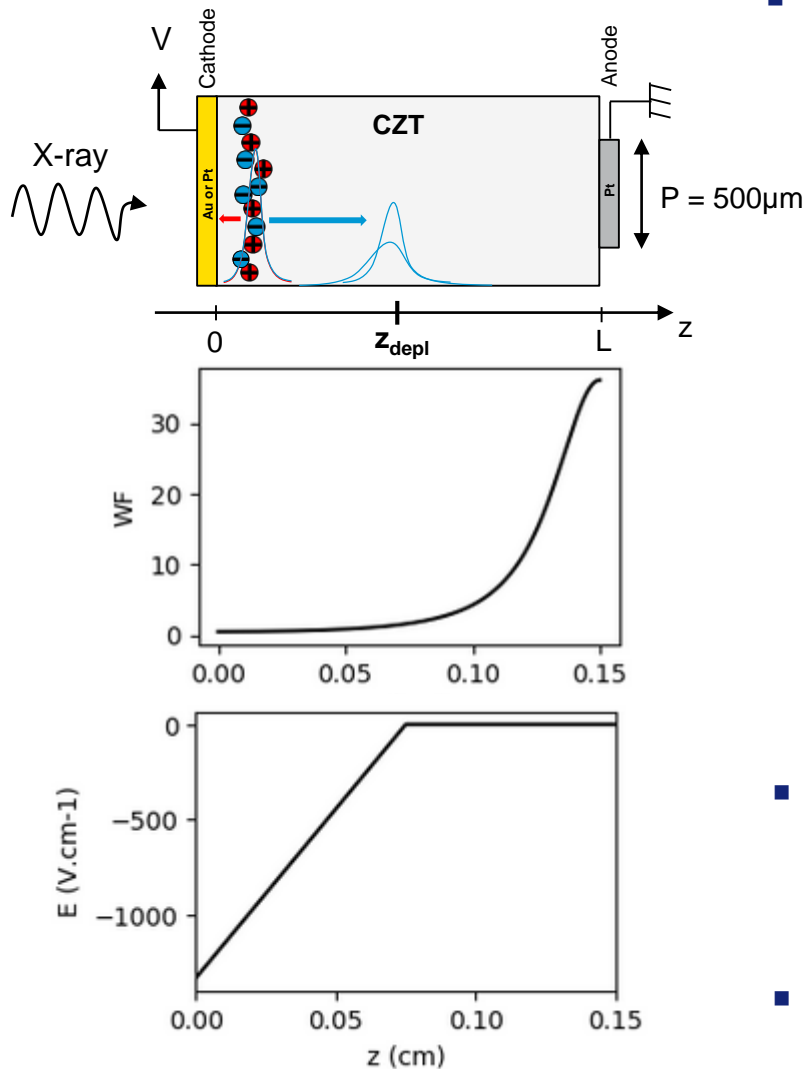
Outlook and ongoing work  
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**V = -500V**

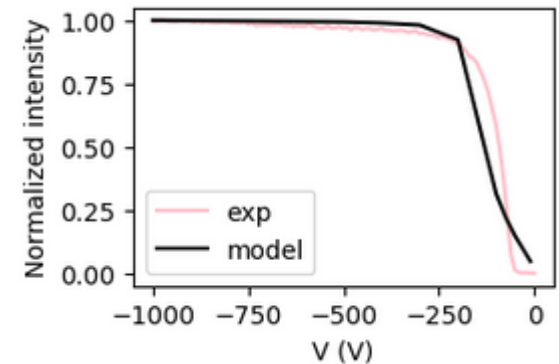
**8keV**





## ■ Analytical model principles

- Electrons and holes clouds are represented as Gaussians
- Drift of both electrons and holes are considered
- Free diffusion of electrons is considered
- Diffusion of holes is not considered (if charges are created outside the depletion region holes are neglected)



## ■ Issues

- Voltage threshold is not explained
- High  $\mu\tau$  needed to fit experimental data

## ■ Further work needed

## ▪ Objectives

- Reduce the leakage current of the devices obtained with HF-CZT
- Characterize the optimized devices

## ▪ Context

- Characterization of 2 HF-CZT devices with optimized electrodes (Au/HF-CZT/Pt and Pt/HF-CZT/Pt) within the IMCZT collaboration

## ▪ Results

- Significantly reduced leakage current ( $<100\text{pA/mm}^2$  @  $-5\text{kV/cm}$   $20^\circ\text{C}$ ) compared with standard Redlen pixelated platinum electrode configuration.
- Stability and repeatability demonstrated under X-ray fluxes up to  $10^{+12}\text{photons.mm}^{-2}.\text{s}^{-1}$
- Linearity demonstrated for  $10^{+7}$ - $10^{+10}\text{photons.mm}^{-2}.\text{s}^{-1}$  flux range
- Afterglow negligible in the seconds time range and stabilization time below 200ms.

## ▪ Ongoing and future work

- Modelization of IV characteristics under X-ray irradiation as a function of incident energy
- Finer afterglow characterization
- Colleagues from Palermo university (L. Abbene and F. Principato) have been characterizing these samples (ITD model and gamma spectroscopy) and will be publishing soon so stay tuned.

**Thank you for you attention !  
Do you have questions?**



**The European Synchrotron**